

Wednesday Afternoon, November 12, 2014

Exhibitor Technology Spotlight

Room: Hall ABC - Session EW-WeA

Exhibitor Technology Spotlight Session

Moderator: Chris Moffitt, Kratos Analytical Limited, UK

4:00pm **EW-WeA6 FOCUS beyond PEEM and NanoESCA, Dieter Pohlenz, M. Escher, M. Weber, FOCUS GmbH, Germany**

FOCUS is an owner-managed German company situated in Hünstetten close to Wiesbaden. Since its establishment in 1990, FOCUS has been engaged in the field of electron beam evaporation, electron spectroscopy and electron microscopy and in scientific apparatus construction generally. Most recent developed products are the focused VUV-source HIS 14 HD and the universal UHV Ion Source FDG 150. The HIS 14 HD source delivers a spot diameter of 300µm for angle resolved photoemission spectroscopy using technology developed at synchrotron beam lines. We list the mounting requirements and show first ARPES results. The FDG 150 is designed for depth profile analysis in XPS- and Auger Spectroscopy and charge neutralization (ESCA). Further applications are sample cleaning and sensor cleaning in scanning probe microscopy and the use as excitation source for ISS/LEIS analysis. The FERRUM spin polarization detector is the latest FOCUS product for spin analysis which can be combined with state of the art electron spectrometers.

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